Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | DITTMAR ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0206722	10-2004	Gruening-Von Schwerin et al.	216/013
*	В	US-6,372,631	04-2002	Wang et al.	438/624
*	С	US-5,173,442	12-1992	Carey, David H.	216/18
*	D	US-6,130,449	10-2000	Matsuoka et al.	257/296
*	Ε	US-6,426,298	07-2002	Chen et al.	438/699
*	F	US-6,720,252	04-2004	Chen et al.	438/636
*	G	US-6,130,449	10-2000	Matsuoka et al.	257/296
*	Н	US-6,727,143	04-2004	Hui et al.	438/256
*	-	US-6,372,614	04-2002	Rangarajan et al.	438/586
*	J	US-5,173,442	12-1992	Carey, David H.	216/18
*	Κ	US-2001/0021552	09-2001	Parekh et al.	438/239
*	L	US-2001/0051408	12-2001	CHIU, YIH-SONG	438/243
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0				·	
	Р					
	Q					
	R					
	S					
	т				·	

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	υ					
	٧					
	8					
	х					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.